

MICRONICS JAPAN CO., LTD.

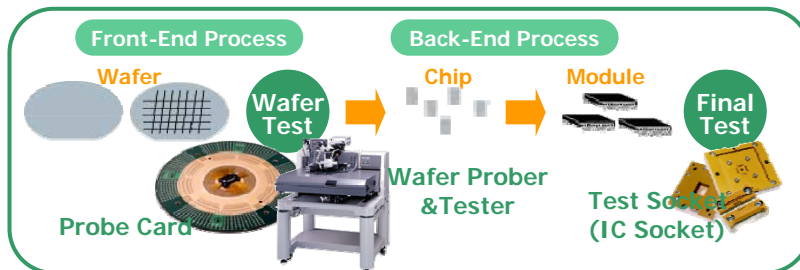
President
MASAYOSHI HASEGAWA

June 15, 2007

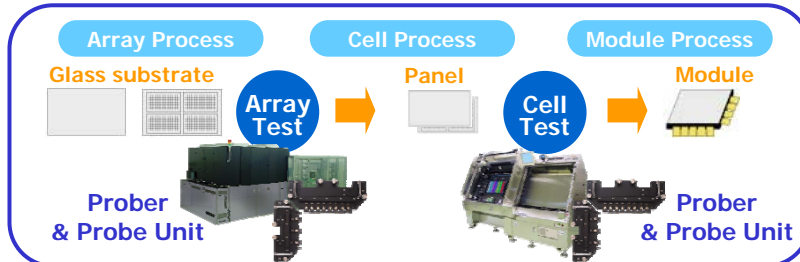


Business Field

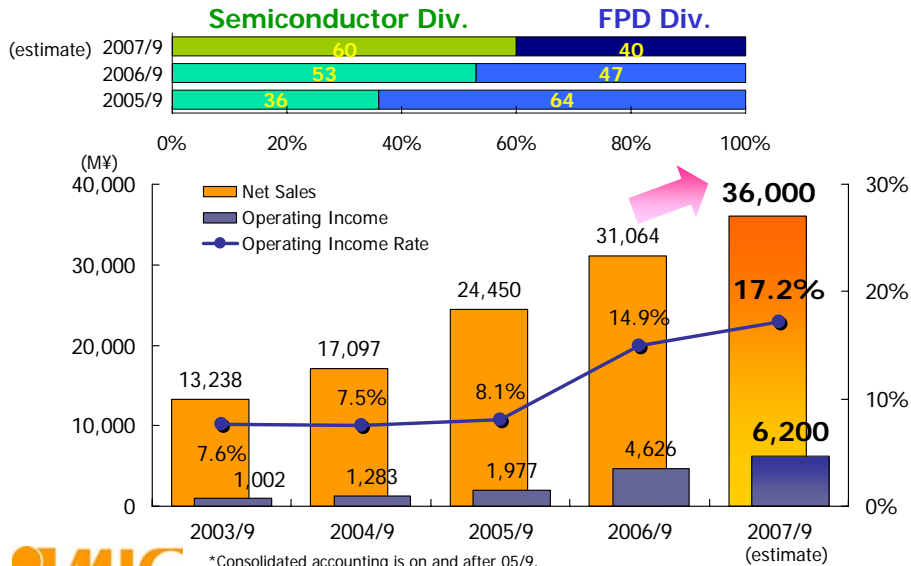
SEMICON
DUCTOR



FPD(LCD)

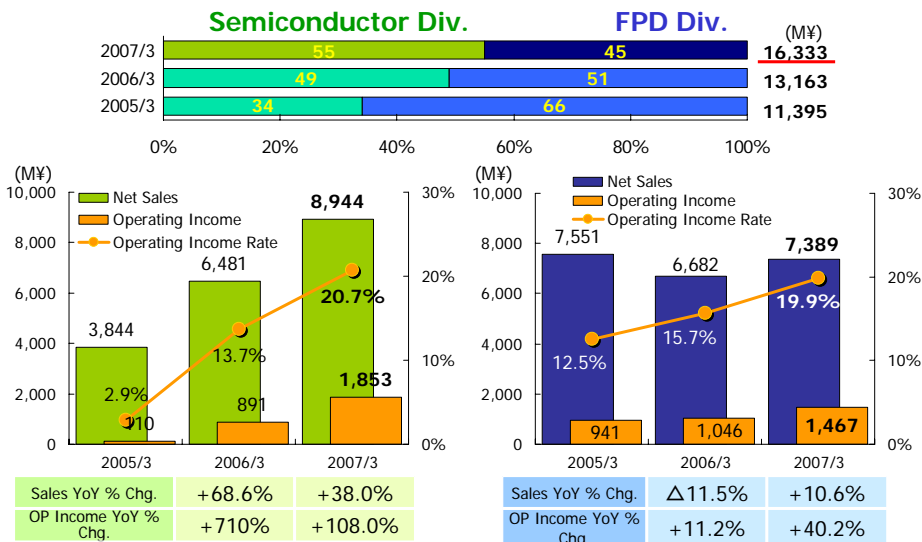


Business Performance Transition

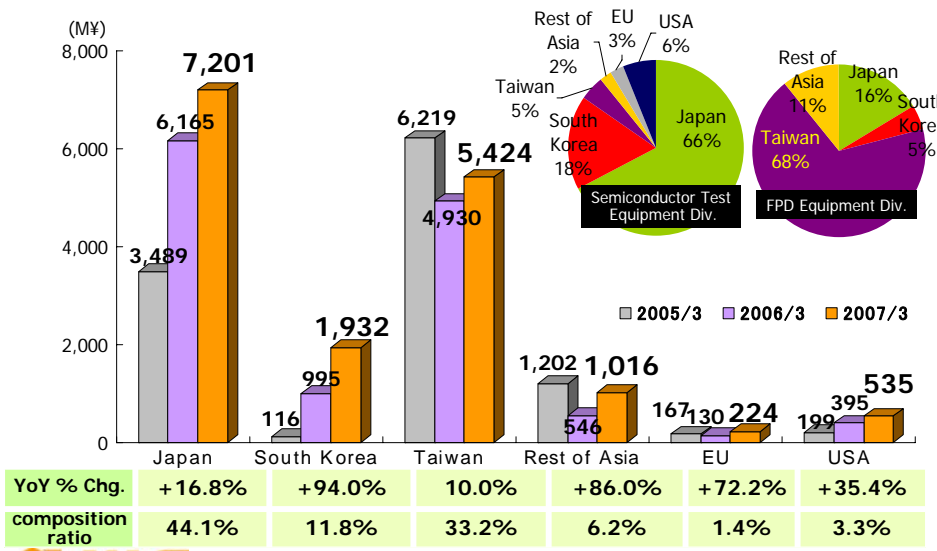


Segment Information

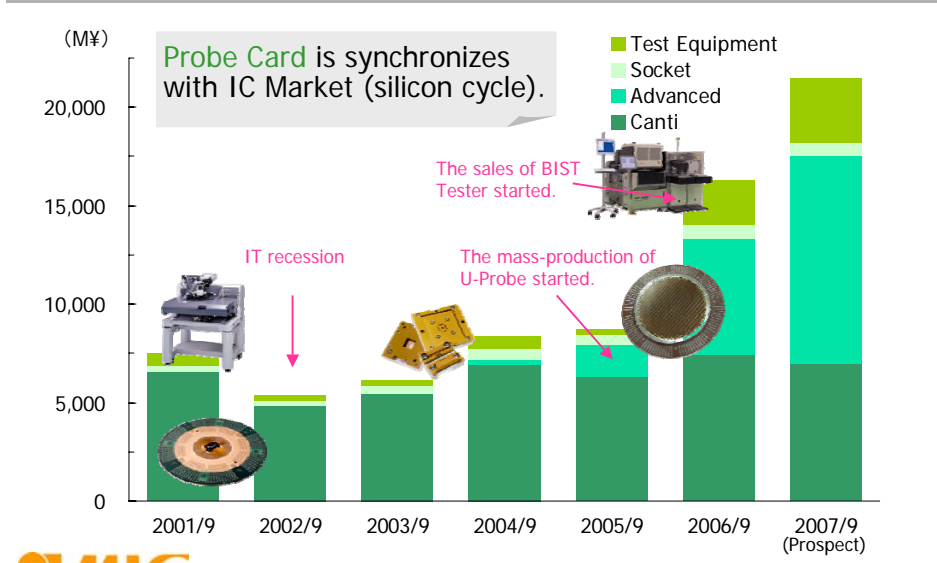
(1H FY2007)



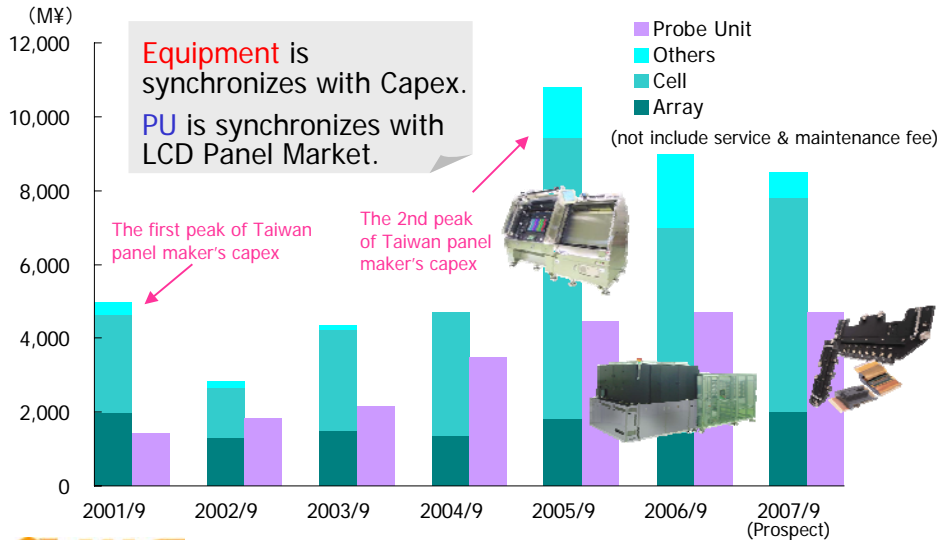
Net Sales by Region (1H FY2007)



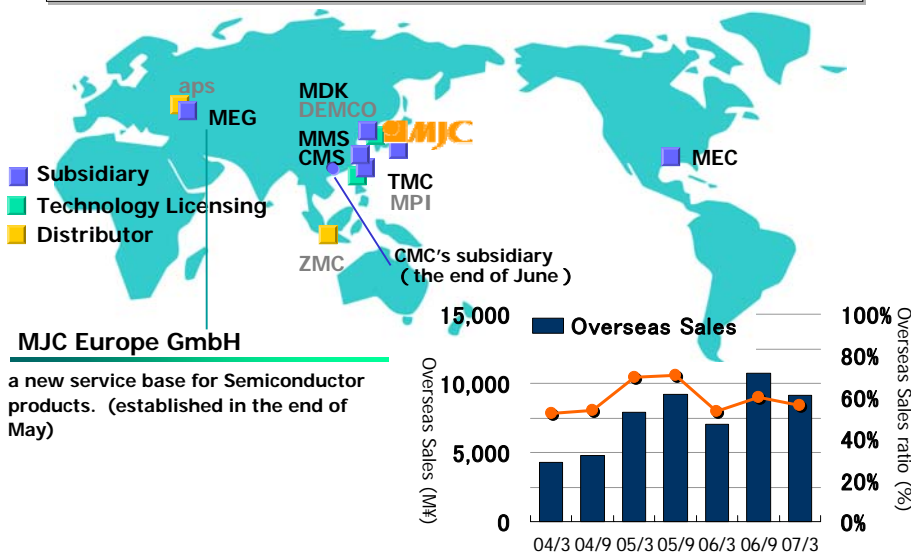
Semiconductor Test Equipment Business



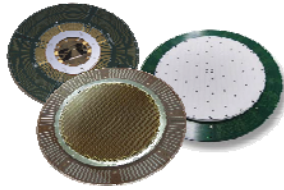
LCD Test Equipment Business



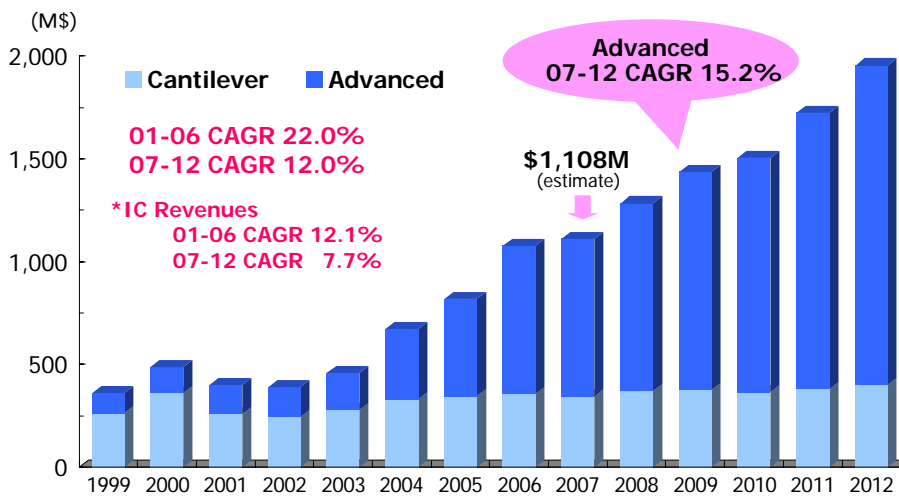
Overseas Strategy



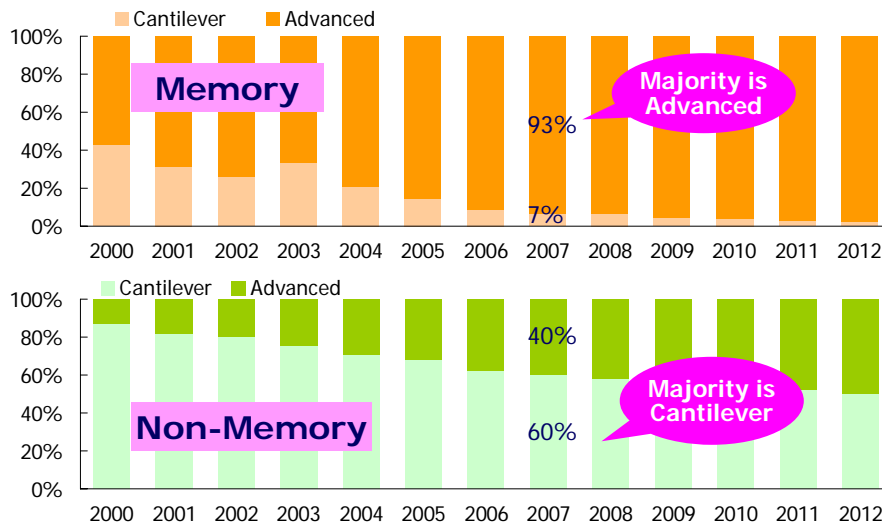
Advanced Probe card



Probe Card Market -by Technology



Probe Card Market -by Application



Source VLSI Research Inc June 2007


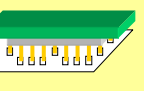
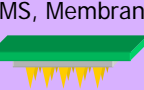


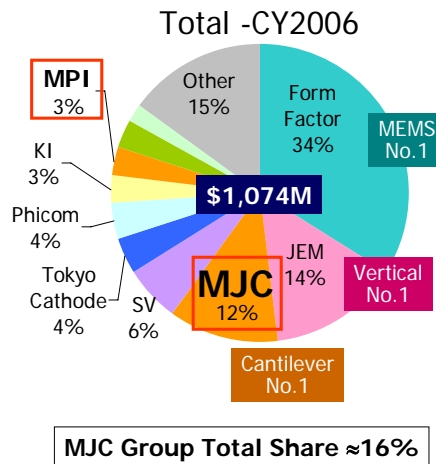
Why Advanced Probe Card

- ✿ Improve Test efficiency
 - Most suitable multi-Die test
 - ex. DRAM Cantilever 64DUT, Vertical 128DUT, MEMS 256DUT/384DUT
- ✿ Response to miniaturized structure Device
 - Fine Pitch, small PAD, etc...
- ✿ Fit the Known Good Die (KGD) Test
 - At-speed Test, Wafer Level Burn IN (WLBI) Test



Probe Card Types & Vendors

	Shape and features	Price	Market	Delivery
Canti	Cantilever-type 	Low ↑	Vendor More ↑	Short ↑
	Vertical-type 			
Advanced	Lithography-type (MEMS, Membrane) 	High ↓	Less ↓	Relatively Long ↓



MJC Group Total Share ≈16%
*include Korea Demco's share 1%

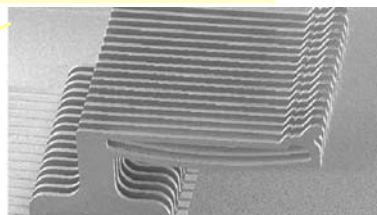
Source VLSI Research Inc June 2007



MJC's MEMS Probe Card

"U-Probe"

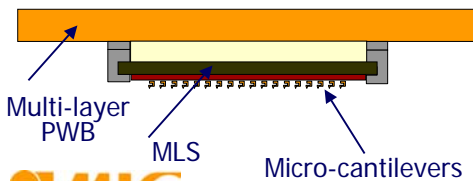
Micro-cantilevers



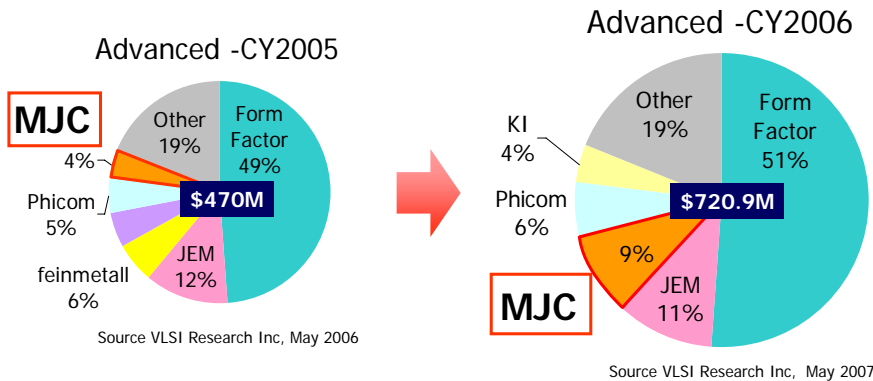
MLS

Ceramic

Thin Film < 100um



MJC Target

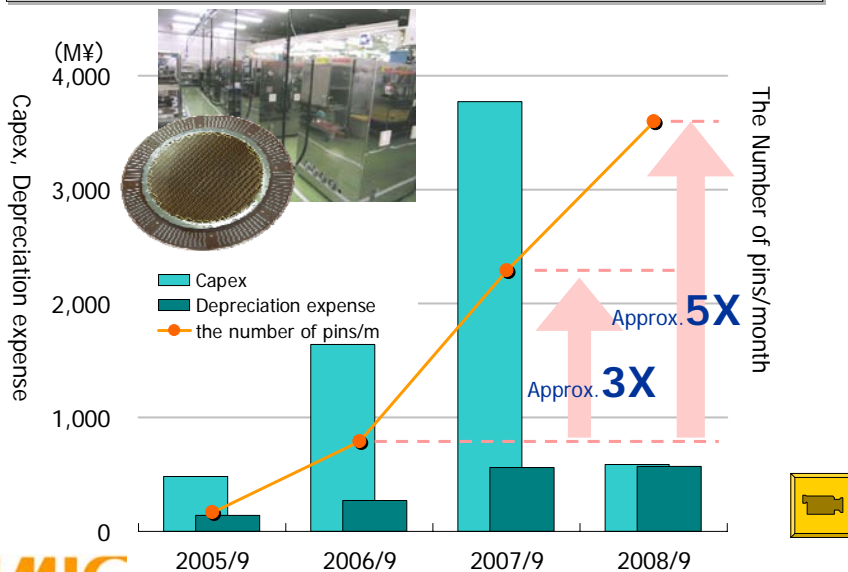


Target in CY 2008 is Share 25% or more.

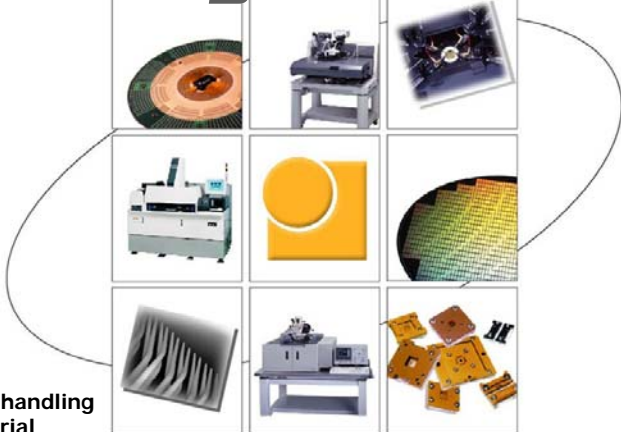
* Share 20% or more of all Probe card.



U-Probe Capex Planning



Probing the Future



Notice in handling this material

Contents in this presentation material such as the product situation in the market are described based on information we can collect at present. Also, our strategy and goals are based on our present situation. Thus, please keep in mind that actual market situation and our future situation may be quite different from the description and information in this presentation material.

